Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/648,800	DEPKE ET AL.	
Examiner	Art Unit	
Matthew L. Fedowitz	1623	

	SEAR	CHED	
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424	9.362	10/5/2005	MLF
424	9.61	10/5/2005	MLF
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534	15	10/5/2005	MLF
514	185	10/5/2005	MLF
514	410	10/5/2005	MLF

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